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		NOTICE OF REFERENCES CITED		APPLICANT(S) Maas			

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*		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	A	4,530,324	7/1985	Tanaka et al.	123	300	
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*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS
	L						
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	O						
	P						
	Q						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	R	
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EXAMINER Carl S. Miller	DATE April 8, 2002	Form892ccs2106b
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05(a).)		

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Application/Control No.

10/051,460

Applicant(s)/Patent Under

Reexamination
FOX ET AL.

Examiner

Emmanuel Sayoc

Art Unit

3746

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NON-PATENT DOCUMENTS

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